

Dual N & P-Channel PowerTrench[®] MOSFET

General Description

These dual N- and P-Channel enhancement mode power field effect transistors are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state ressitance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

• Q1: N-Channel

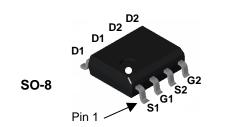
7.0A, 30V $R_{DS(on)} = 0.028\Omega @ V_{GS} = 10V$ $R_{DS(on)} = 0.040\Omega @ V_{GS} = 4.5V$

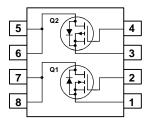
• Q2: P-Channel

5A, -30V
$$R_{DS(on)} = 0.052\Omega @ V_{GS} = -10V$$

 $R_{DS(on)} = 0.080\Omega @ V_{GS} = -4.5V$

- Fast switching speed
- High power and handling capability in a widely used surface mount package





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Q1	Q2	Units	
V _{DSS}	Drain-Source Voltage			30	30	V	
V _{GSS}	Gate-Source Voltage			±20	±20	V	
I _D	Drain Curre	nt - Continuous	(Note 1a)	7	-5	А	
		- Pulsed		20	-20		
PD	P _D Power Dissipation for Dual Operation				W		
	Power Dissipation for Single Operation (Note 1a)		1.6				
			(Note 1b)		1		
			(Note 1c)	C).9		
T _J , T _{STG}	Operating and Storage Junction Temperature Range -5			-55 to	o +150	°C	
Therma R _{0JA}	I Charac	teristics sistance, Junction-to-Ambi	ent (Note 1a)		78	°C/W	
R _{θJC}	Thermal Resistance, Junction-to-Case (Note 1)			40		°C/W	
Packag	e Marking	g and Ordering Ir	nformation				
Device Marking		Device	Reel Size	Tape wi	dth	Quantity	
FDS8958A		FDS8958A	13"	12mn	n	2500 units	

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Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Off Cha	racteristics				•	•	•
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_D = 250 \mu A$ $V_{GS} = 0 V, I_D = -250 \mu A$	Q1 Q2	30 -30			V
<u>ΔBVdss</u> ΔTJ	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25° C $I_D = -250 \ \mu$ A, Referenced to 25° C	Q1 Q2		25 -22		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 V, V_{GS} = 0 V$ $V_{DS} = -24 V, V_{GS} = 0 V$	Q1 Q2			1 -1	μΑ
IGSSF	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$	All			100	nA
	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$	All			-100	nA
On Cha	racteristics (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$ $V_{DS} = V_{GS}, I_D = -250 \ \mu A$	Q1 Q2	1 -1	1.6 -1.7	3 -3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25°C $I_D = -250 \ \mu$ A, Referenced to 25°C	Q1 Q2		-4.3 4		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance		Q1		21 32 27	28 42 40	mΩ
		$ \begin{array}{l} V_{GS} = -10 \; V, \; I_D = -5 \; A \\ V_{GS} = -10 \; V, \; I_D = -5 \; A, \; T_J = 125^\circ C \\ V_{GS} = -4.5 \; V, \; I_D = -4 \; A \end{array} $	Q2		41 58 58	52 78 80	
I _{D(on)}		$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$ $V_{GS} = -10 \text{ V}, V_{DS} = -5 \text{ V}$	Q1 Q2	20 -20			A
g fs	Forward Transconductance	V _{DS} = 5 V, I _D = 7 A V _{DS} = -5 V, I _D =-5 A	Q1 Q2		19 11		S
Dynami	c Characteristics						
C _{iss}	Input Capacitance	Q1 V _{DS} = 10 V, V _{GS} = 0 V, f = 1.0 MHz	Q1 Q2		789 690		pF
C _{oss}	Output Capacitance	Q2	Q1 Q2		173 306		pF
C _{rss}	Reverse Transfer Capacitance	V_{DS} = -10 V, V_{GS} = 0 V, f = 1.0 MHz	Q1 Q2		66 77		pF

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Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Switchir	ng Characteristics (Note	2)					
t _{d(on)}	Turn-On Delay Time	Q1	Q1		2.2	4.4	ns
-()		$V_{DD} = 10 V, I_D = 1 A,$	Q2		6.7	13.4	
t _r	Turn-On Rise Time	$V_{GS} = 10V, R_{GEN} = 6 \Omega$	Q1		7.5	15	ns
			Q2		9.7	19.4	
t _{d(off)}	Turn-Off Delay Time	Q2	Q1		11.8	21.3	ns
	-	$V_{DD} = -10 V, I_D = -1 A,$	Q2		19.8	35.6	
t _f	Turn-Off Fall Time	V_{GS} = -10V, R_{GEN} = 6 Ω	Q1		3.7	7.4	ns
			Q2		12.3	22.2	
Qg	Total Gate Charge	Q1	Q1		16	26	nC
-	_	$V_{DS} = 15 \text{ V}, I_D = 7 \text{ A}, V_{GS} = 10 \text{ V}$	Q2		14	23	
Q _{gs}	Gate-Source Charge		Q1		2.5		nC
		Q2	Q2		2.4		
Q _{gd}	Gate-Drain Charge	$V_{DS} = -15 \text{ V}, I_D = -5 \text{ A}, V_{GS} = -10 \text{ V}$	Q1		2.6		nC
			Q2		4.8		
Drain-S	ource Diode Character	istics and Maximum Ratings	5				
ls	Maximum Continuous Drain-S	num Continuous Drain-Source Diode Forward Current				1.3	Α
-			Q2			-1.3	
V _{SD}	Drain-Source Diode Forward	$V_{GS} = 0 V, I_S = 1.3 A$ (Note 2)	Q1		0.74	1.2	V
00	Voltage	$V_{GS} = 0 V, I_S = -1.3 A$ (Note 2)	Q2		-0.76	-1.2	

Notes:

1. R_{6JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{6JC} is guaranteed by design while R_{6CA} is determined by the user's board design.



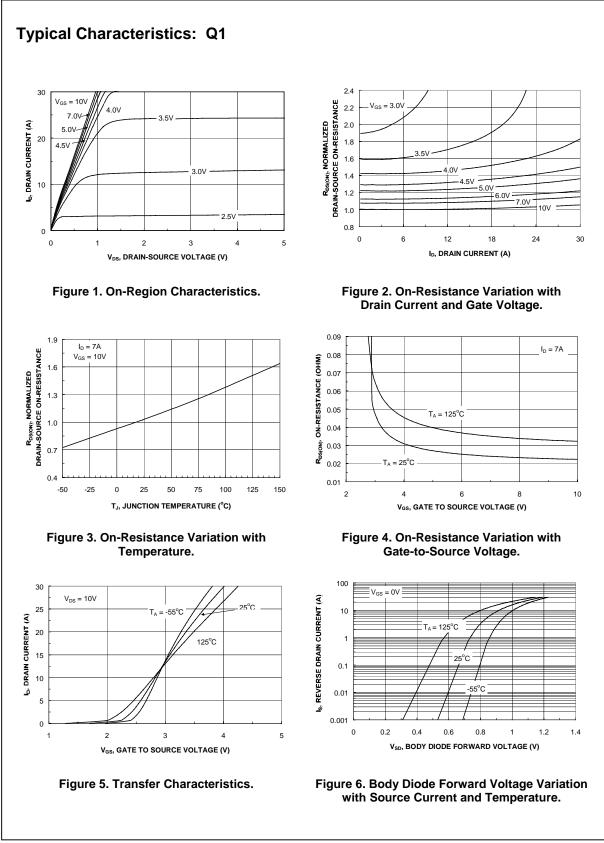
a) 78°/W when mounted on a 0.5 in² pad of 2 oz copper

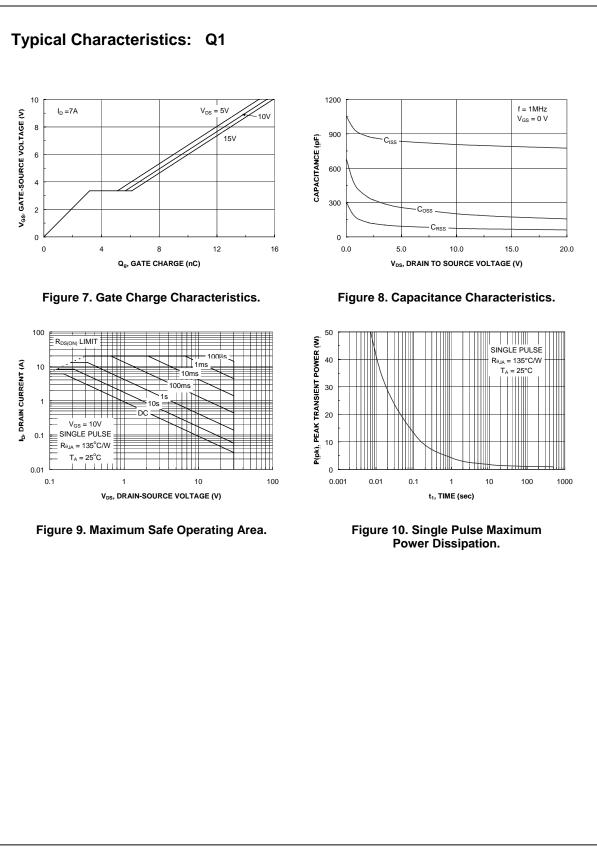
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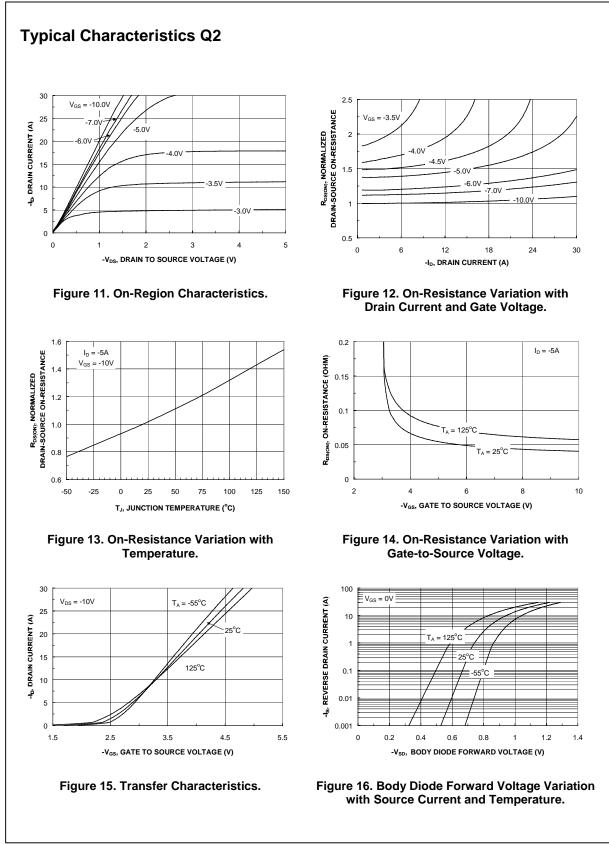
 b) 125°/W when mounted on a .02 in² pad of 2 oz copper c) 135°/W when mounted on a minimum pad.

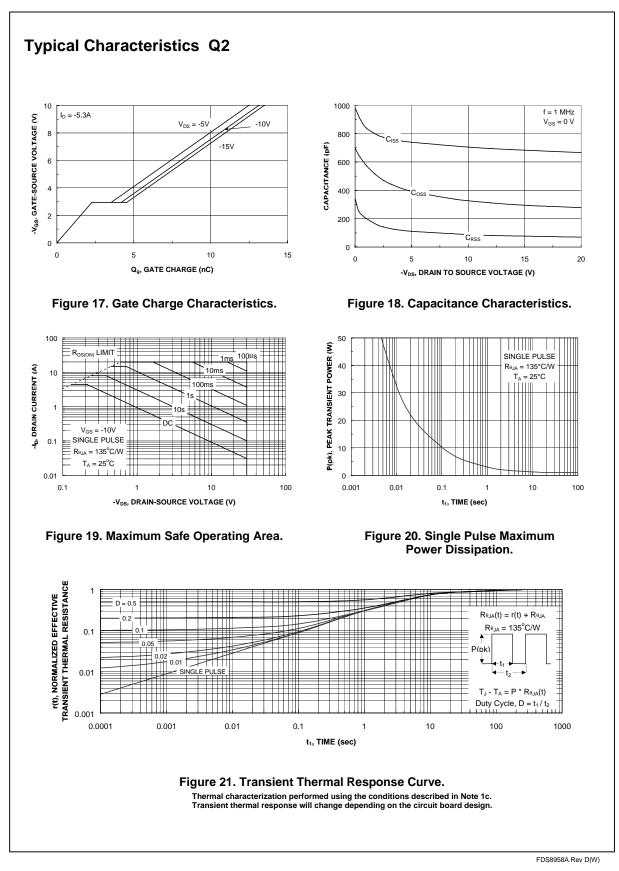
Scale 1 : 1 on letter size paper

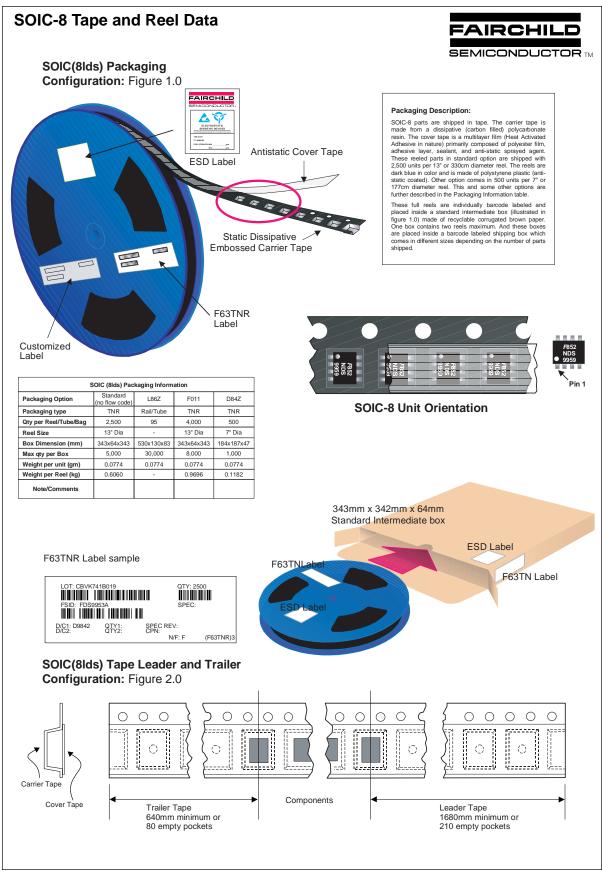
2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%





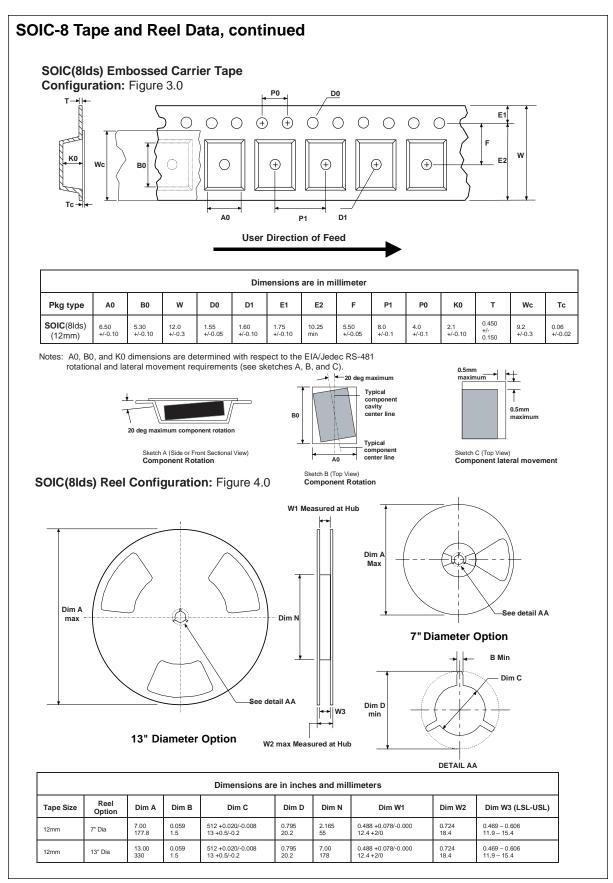


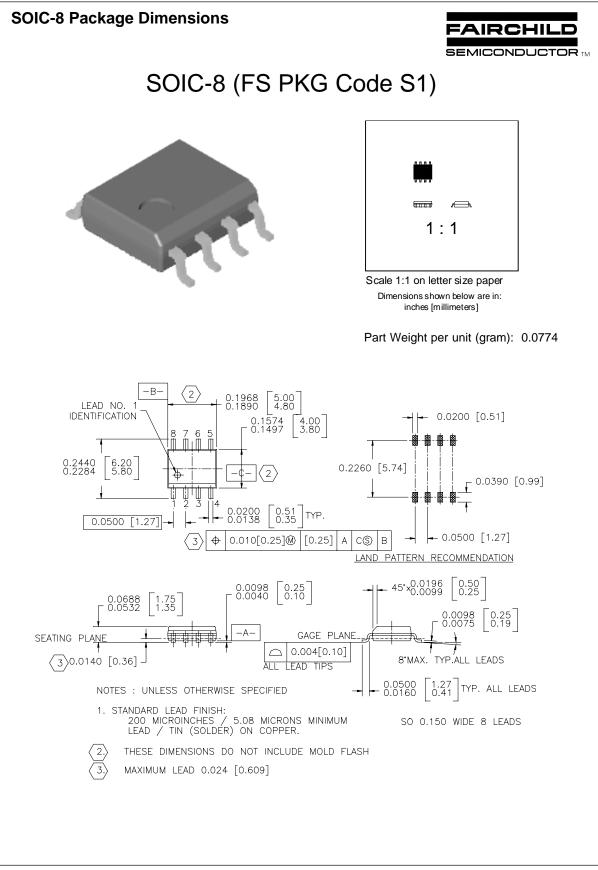




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